

A scanning electron micrograph (SEM) of a 28nm CMOS die. The die is square and shows a complex pattern of metal interconnects and semiconductor structures. The image is overlaid with a grid. A scale bar at the bottom left indicates 2 µm. Metadata text is visible in the lower-left quadrant.

Q Vendor GLOBALFOUNDRIES

Q Product GF018hw5v\_green\_sq0

Q Version 2015q2v2

Q Metric 1.00

2 µm